

## **LA-ICP-MS Imaging of Heterogeneous Volcanic Glass: Method and Applications**

JEFFREY OALMANN\*, MARCUS PHUA, CAROLINE  
BOUVET DE MAISONNEUVE

Earth Observatory of Singapore and Asian School of the  
Environment, Nanyang Technological University, 50  
Nanyang Avenue, N2-01B-30, Singapore 639798  
(\*correspondence: joalmann@ntu.edu.sg;  
phua0118@e.ntu.edu.sg; carolinebouv@ntu.edu.sg)

Trace element compositions of volcanic glass shards are widely used for tephrostratigraphic and volcanic studies. However, traditional LA-ICP-MS spot analyses can be complicated by the presence of microscale heterogeneities, including microlites, inclusions, and compositional banding. For example, the accidental ablation of unidentified, subsurface microlites results in inaccurate glass compositions. We present a method in which these heterogeneities can be identified and used to better correlate volcanic units and understand magmatic processes.

Firstly, BSE and EDS images of glass shards in polished epoxy mounts are collected and used to identify heterogeneities and guide point placement for EPMA analyses. Then, trace element data are collected by rastering the sample stage at 5  $\mu\text{m}/\text{second}$  under a 10  $\mu\text{m}$  laser spot with 10 Hz repetition rate and 4.5  $\text{J}/\text{cm}^2$  fluence, resulting in a  $\sim 1$   $\mu\text{m}$  deep ablation area. Finally, the raw data are processed into quantitative maps using the built-in functions of the Iolite software package [1,2,3], and trace element compositions from regions of interest are extracted using the Monocle plug-in for Iolite [4].

Trace element concentrations of homogenous reference glasses measured using this mapping technique have similar or better precision ( $\leq 5\%$  RSD) and accuracy ( $\pm 10\%$  of accepted values) than measurements made by spot analyses for most elements. Unidentified, subsurface heterogeneities are avoided due to the shallow depth of ablation, and the mapped heterogeneities can either be integrated into or excluded from the calculated glass compositions. Furthermore, the trace element compositions of microlites and inclusions can be quantified, providing additional information from a single glass particle. This technique provides an improved way to quantify the trace element concentrations of volcanic glass shards and visualize and exploit the heterogeneities of tephra particles.

[1] Paton et al. (2011), *JAAS* 26, 2508-2418. [2] Paul et al. (2012), *JAAS* 27, 700-706. [3] Paul et al. (2014), *GGR* 38, 253-263. [4] Petrus et al. (2017), *Chem Geol* 463, 76-93.